The Third Day	: 6.16 (Wed.) 8	8:00	9:00 10:00	11:00 12:00			15:00	16:00	17:00	18:00	19:00	20:00
A会場	2F Main Convention Hall		S-1 International Symposium on Advanced Electron Microscopy in Asia 9:00~12:15			S-1 International Symposium on Advanced Electron Microscopy in Asia 13:15~17:25						
B会場	2F Medium hall 200		Nanotechnology Pla Years of Activities a Achievement of Adv Characterization Na Platform	and vanced		Nanotechnology Pla Years of Activities at Achievement of Adv Characterization Na Platform	nd vanced					
C会場	3F Medium hall 300		B-2 Microorganisms, Cells & Tissues Imaging/Sample Preparation 9:00~12:00			S-6 The frontiers of cryo-SEM observation of vitrified frozen-hydrated specimen for biological and soft- material sciences 13:00~17:00						
D会場	2F Medium conference room 201		Retrieval, Ph Phase Plate, Lorentz-Micr	I-4 Phase-Related Topics (Phase Retrieval, Phase Detection, Phase Plate, Holography, Lorentz-Microscopy & Others) 9:30~11:45		M-8 In-situ Observation & Environmental Microscopy 13:00~16:15						
E会場	2F Medium conference room 202		I-8 Others (Instrumen 9:00~11:45	nts & Methods)		I-2 SEM 13:00~14:15	M-1 Metals & all 14:30~16:					
F会場	1F Main conference room 101		FIB-SEM as Observa	Technological Trends in AdvancedFIB-SEM as Observation andMicrofabrication Instrument		S-11 Cutting-Edge Technologies in Electron Interference Microscopy 13:00~17:00						
G会場	4F Small meeting room 405											